

Notice of References Cited	Application/Control No. 10/799,118	Applicant(s)/Patent Under Reexamination MEYER ET AL.	
	Examiner Sebastiano Passaniti	Art Unit 3711	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,431,396	07-1995	Shieh, Tien W.	473/329
*	C	US-5,411,255	05-1995	Kurashima et al.	473/332
*	D	US-5,316,298	05-1994	Hutin et al.	473/332
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages),
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